MOSFET - Power, N-Channel, Shielded Gate 60 V, 5.2 m Ω , 78 A

NTTFS5D1N06HL

General Description

This N-Channel MOSFET is produced using ON Semiconductor's advanced MOSFET process that incorporates Shielded Gate technology. This process has been optimized to minimize on-state resistance and yet maintain superior switching performance with best in class soft body diode.

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)} = 5.2 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 16 \text{ A}$
- Max $r_{DS(on)} = 7.1 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 13 \text{ A}$
- Lowers Switching Noise/EMI
- MSL1 Robust Package Design
- 100% UIL Tested
- RoHS Compliant

Applications

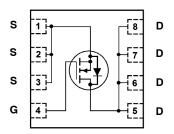
- Primary DC-DC MOSFET
- Synchronous Rectifier in DC-DC and AC-DC
- Motor Drive



ON Semiconductor®

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ELECTRICAL CONNECTION



N-Channel MOSFET



(3.3x3.3, 0.65 P) CASE 511DY

MARKING DIAGRAM



 1N06
 = Device Code

 A
 = Assembly Location

 Y
 = Year Code

 WW
 = Work Week Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

MOSFET MAXIMUM RATINGS ($T_A = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter				Ratings	Unit
V _{DS}	Drain to Source Voltage				60	V
V _{GS}	Gate to Source \	Gate to Source Voltage			±20	V
I _D	Drain Current	-Continuous	T _C = 25°C	(Note 5)	78	Α
		-Continuous	T _C = 100°C	(Note 5)	49	
		-Continuous	T _A = 25°C	(Note 1a)	18	
		-Pulsed		(Note 4)	216	
E _{AS}	Single Pulse Ava	lanche Energy		(Note 3)	72	mJ
P _D	Power Dissipatio	n	T _C = 25°C		63	W
	Power Dissipatio	n	T _A = 25°C	(Note 1a)	3.2	
T _J , T _{STG}	Operating and Storage Junction Temperature Range				-55 to +150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case	2	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	39	

PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
1N06	NTTFS5D1N06HL	WDFN8 (3.3x3.3)	7"	12 mm	1500 Units

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
FF CHARACT	ERISTICS					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	60			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, referenced to 25°C		37		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 48 V, V _{GS} = 0 V			10	μΑ
I _{GSS}	Gate to Source Leakage Current	V _{GS} = +20 V, V _{DS} = 0 V			100	nA
N CHARACTE	ERISTICS					
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 80 \mu A$	1.2	1.6	2.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 80 μA, referenced to 25°C		-5.2		mV/°C
r _{DS(on)}	Static Drain to Source On	V _{GS} = 10 V, I _D = 16 A		4.4	5.2	mΩ
	Resistance	V _{GS} = 4.5 V, I _D = 13 A		5.6	7.1	
YNAMIC CHA	RACTERISTICS					
C _{ISS}	Input Capacitance	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V},$		1610		pF
C _{OSS}	Output Capacitance	f = 1 MHz		313		
C _{RSS}	Reverse Transfer Capacitance			12.2		
R _G	Gate Resistance			0.9		Ω

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted) (continued)

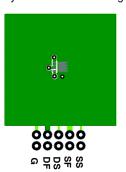
Symbol	Parameter	Parameter Test Condition		Min	Тур	Max	Units
SWITCHING CH	IARACTERISTICS	•	•		•		
t _{d(ON)}	Turn – On Delay Time	$V_{DD} = 30 \text{ V, } I_{D} = 16 \text{ A,}$ $V_{GS} = 4.5 \text{ V, } R_{GEN} = 2.5 \Omega$			14		ns
t _{rd(ON)}	Rise Time				24		
t _{d(OFF)}	Turn – Off Delay Time				41.3		
t _f	Fall Time				12.2		1
Qg	Total Gate Charge	V _{GS} = 0V to 10 V			22.5		nC
Qg	Total Gate Charge	V _{GS} = 0V to 4.5 V			10.3		1
Q _{gs}	Gate to Source Charge	V _{DD} = 30 V I _D = 16 A			5		1
Q _{gd}	Gate to Drain "Miller" Charge				3		1
DRAIN-SOURC	E DIODE CHARACTERISTICS	•			-	-	-
V _{SD}	Source to Drain Diode Forward	V _{GS} = 0 V, I _S = 16 A	(Note 2)		0.8	1.2	V
	Voltage	V _{GS} = 0 V, I _S = 16 A	(Note 2)		0.66		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

 t_{rr}

 Q_{rr}

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 \times 1.5 in. board of FR-4 material. $R_{\theta CA}$ is determined by the user's board design.



a) 53°C/W when mounted on a 1 in² pad of 2 oz copper.

Reverse Recovery Time

Reverse Recovery Charge



b) 125°C/W when mounted on a minimum pad of 2 oz copper.

35.1

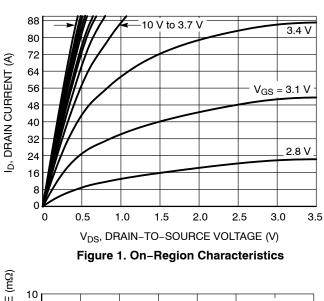
37

ns

nC

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%. 3. E_{AS} of 72 mJ is based on starting T_J = 25°C; L = 1 mH, I_{AS} = 12 A, V_{DD} = 48 V, V_{GS} = 10 V. 100% test at L = 1 mH, I_{AS} = 12 A.
- 4. Pulsed I_D please refer to SOA graph for more details.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

TYPICAL CHARACTERISTICS



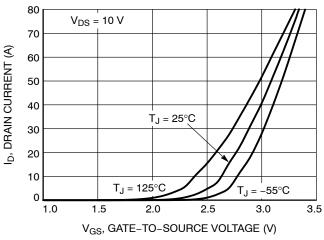
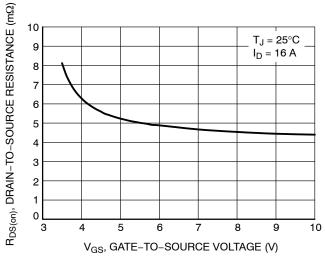


Figure 2. Transfer Characteristics



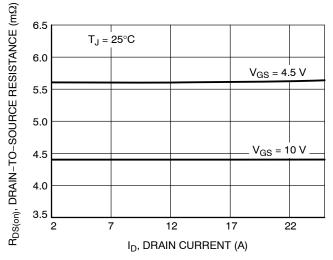
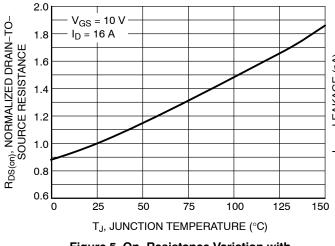


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



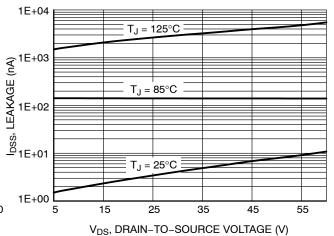


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

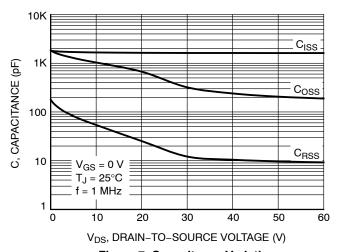


Figure 7. Capacitance Variation

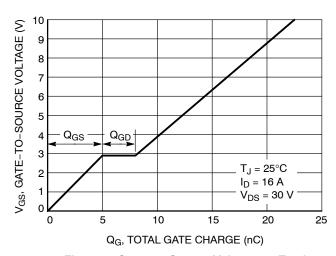


Figure 8. Gate-to-Source Voltage vs. Total Charge

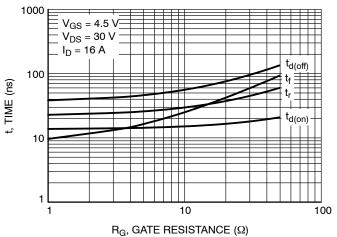


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

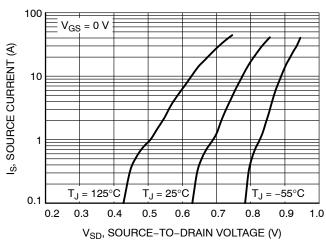


Figure 10. Diode Forward Voltage vs. Current

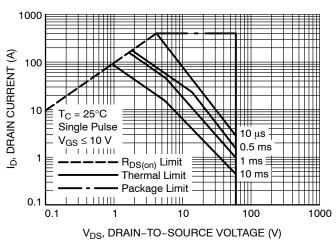


Figure 11. Maximum Rated Forward Biased Safe Operating Area

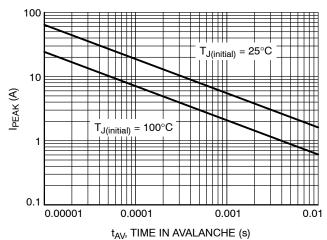


Figure 12. Maximum Drain Current vs. Time in Avalanche

TYPICAL CHARACTERISTICS

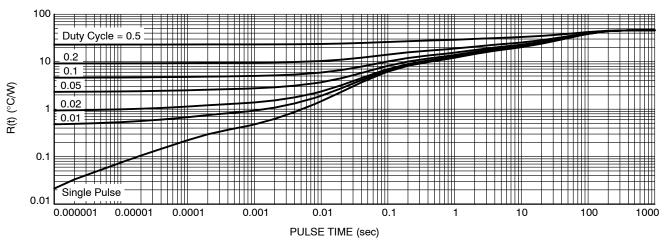
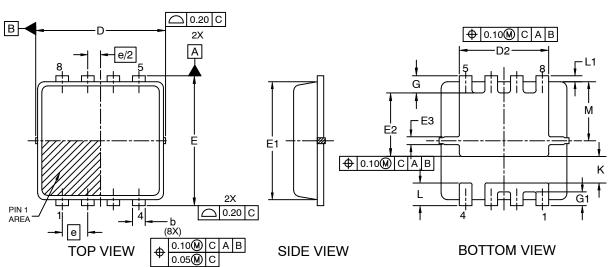


Figure 13. Transient Thermal Impedance

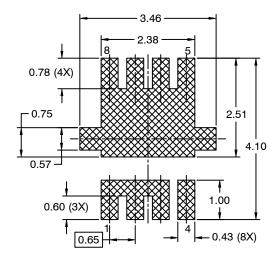
PACKAGE DIMENSIONS

WDFN8 3.3x3.3, 0.65PCASE 511DY ISSUE A



(4X) Θ D1 Λ (8X) Δ 0.10 C SEATING PLANE

END VIEW



RECOMMENDED LAND PATTERN

NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETERS
- 2. DIMENSIONS D1 & E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS NOR GATE BURRS.

DIM	MILLIMETERS				
וווטן	MIN	NOM	MAX		
Α	0.70	0.75	0.80		
A1	0.00	-	0.05		
b	0.23	0.33	0.43		
С	0.15	0.20	0.25		
D	3.20	3.30	3.40		
D1	2.95	3.13	3.30		
D2	1.98	2.20	2.40		
Е	3.20	3.30	3.40		
E1	2.80	3.00	3.15		
E2	1.40	1.60	1.80		
E3	0.15	0.25	0.40		
е	0	С			
G	0.30	0.43	0.55		
G1	0.25	0.35	0.45		
K	0.55	0.75	0.95		
L	0.35	0.52	0.65		
L1	0.06	0.15	0.30		
М	1.35	1.50	1.60		
θ	0	_	12		

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